

# 30V Dual Asymmetric N-Channel Enhancement Mode MOSFET

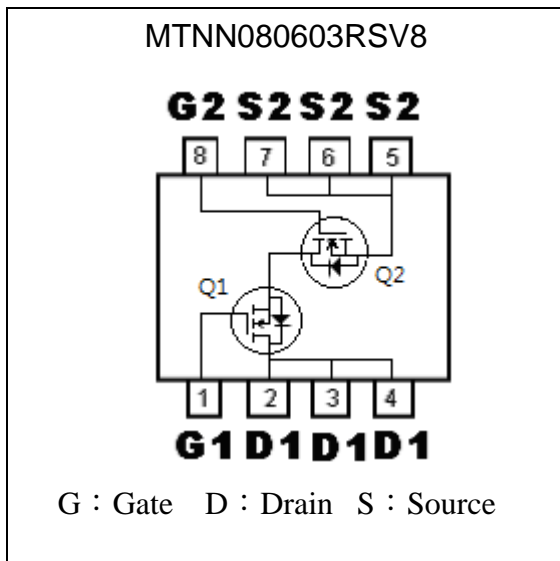
## MTNN080603RSV8

	Q1	Q2
$BV_{DSS}$	30V	30V
$I_D$ @ $T_C=25\text{ }^\circ\text{C}$ , $V_{GS}=10\text{V}$	20A	30A
$I_D$ @ $T_A=25\text{ }^\circ\text{C}$ , $V_{GS}=10\text{V}$	12.8A	14.2A
$R_{DS(on)}$ (typ.) @ $V_{GS}=10\text{V}$	8.8m $\Omega$	5.8m $\Omega$
$R_{DS(on)}$ (typ.) @ $V_{GS}=4.5\text{V}$	12.0m $\Omega$	8.8m $\Omega$

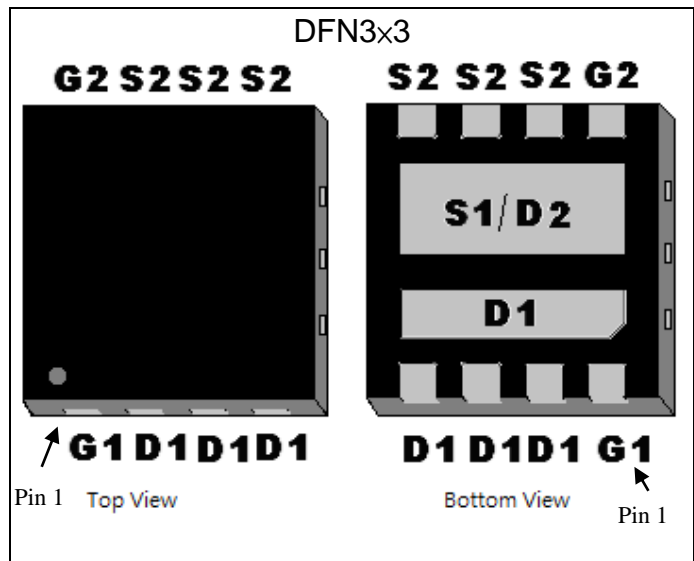
### Features

- High Current Capability
- Low On-resistance
- Fast Switching Characteristic
- Low Gate Charge
- Pb-free lead plating and halogen-free package

### Equivalent Circuit

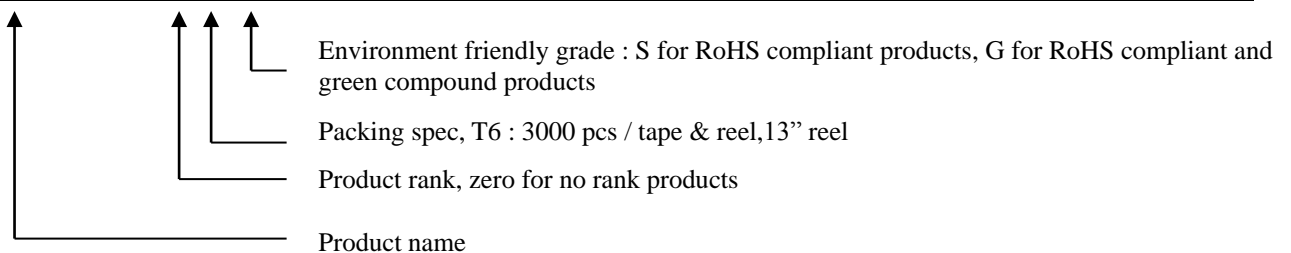


### Outline



### Ordering Information

Device	Package	Shipping
MTNN080603RSV8-0-T6-G	DFN3x3 (Pb-free lead plating and halogen-free package)	3000 pcs / Tape & Reel





**Absolute Maximum Ratings** (Tc=25°C, unless otherwise noted)

Parameter		Symbol	Limits		Unit
			Q1	Q2	
Drain-Source Breakdown Voltage		BVDSS	30	30	V
Gate-Source Voltage		VGS	±20	±20	
Continuous Drain Current	TA=25 °C, VGS=10V *2	IDSM	12.8	14.2	A
	TA=70 °C, VGS=10V *2		10.2	12.7	
	TA=25 °C, VGS=10V		8.6	10	
	TA=70 °C, VGS=10V		6.9	8	
Continuous Drain Current	Tc=25 °C, VGS=10V (silicon limit)	ID	38	44	A
	Tc=100 °C, VGS=10V (silicon limit)		24	27.8	
	Tc=25 °C, VGS=10V (package limit)		20	30	
Pulsed Drain Current * 1		IDM	80	120	
Single Pulse Avalanche Current @ L=0.5mH		IAS	8	9	
Single Pulse Avalanche Energy @ L=1mH *3		EAS	32	32	mJ
Total Power Dissipation	TA=25°C, t<10s	PDSM	2.5	2.5	W
	TA=70°C, t<10s		1.6	1.6	
	TA=25°C, steady state		1.1	1.2	
	TA=70°C, steady state		0.7	0.8	
	Tc=25°C	PD	23	25	
	Tc=100°C		9.2	10	
Operating Junction and Storage Temperature Range		Tj; Tstg	-55~+150		°C

**Thermal Data**

Parameter	Symbol	Q1	Q2	Unit
Max. Thermal Resistance, Junction-to-ambient, t<10s *2	Rth,j-a	50	50	°C/W
Max. Thermal Resistance, Junction-to-ambient, steady state *2		110	100	
Max. Thermal Resistance, Junction-to-case	Rth,j-c	5.4	5	

- Note : 1. Pulse width limited by maximum junction temperature.  
 2. Surface mounted on a 1 in<sup>2</sup> pad of 2oz copper, t≤10s. In practice Rth,j-a will be determined by customer's PCB characteristics.  
 3. 100% tested by conditions of L=0.5mH, VDS=15V, VGS=10V, IAS=3A

**Q1 Electrical Characteristics (Tc=25°C, unless otherwise specified)**

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>					
BVDSS	30	-	-	V	VGS=0V, ID=250µA
VGS(th)	1.2	-	2.5		VDS = VGS, ID=250µA
GFS *1	-	10.2	-	S	VDS =5V, ID=10A
IGSS	-	-	±100	nA	VGS=±20V, VDS=0V
IDSS	-	-	1	µA	VDS =24V, VGS =0V
	-	-	10		VDS =24V, VGS =0V, Tj=55°C
RDS(ON) *1	-	8.8	12	mΩ	VGS =10V, ID=12A
	-	12	18		VGS =4.5V, ID=9A



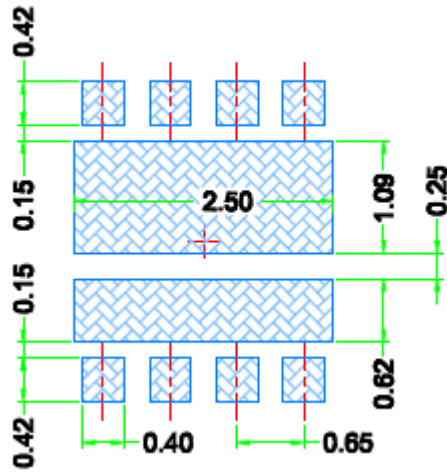
Dynamic					
Ciss	-	568	-	pF	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz
Coss	-	423	-		
Crss	-	53	-		
Qg *1, 2	-	10.6	-	nC	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>D</sub> =12A
Qgs *1, 2	-	2	-		
Qgd *1, 2	-	2.1	-		
td(ON) *1, 2	-	6.8	-	ns	V <sub>DS</sub> =15V, I <sub>D</sub> =12A, V <sub>GS</sub> =10V, R <sub>GS</sub> =1 Ω
tr *1, 2	-	12.6	-		
td(OFF) *1, 2	-	18.8	-		
tf *1, 2	-	5.4	-		
Rg	-	0.6	-	Ω	f=1MHz
Source-Drain Diode					
I <sub>S</sub> *1	-	-	20	A	
V <sub>SD</sub> *1	-	0.85	1.1	V	I <sub>S</sub> =10A, V <sub>GS</sub> =0V
t <sub>rr</sub>	-	15.8	-	ns	I <sub>F</sub> =10A, V <sub>GS</sub> =0V, dI <sub>F</sub> /dt=100A/μs
Q <sub>rr</sub>	-	5.2	-	nC	

**Q2 Electrical Characteristics (T<sub>c</sub>=25°C, unless otherwise specified)**

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static					
B <sub>V</sub> D <sub>SS</sub>	30	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
V <sub>GS(th)</sub>	1.2	-	2.5		V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
I <sub>GSS</sub>	-	-	±10	μA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
I <sub>DSS</sub>	-	-	1		V <sub>DS</sub> =24V, V <sub>GS</sub> =0V
	-	-	10		V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>j</sub> =55°C
*R <sub>DS(ON)</sub>	-	5.8	8.2	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =15A
	-	8.8	13.5		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A
*G <sub>FS</sub>	-	11.2	-	S	V <sub>DS</sub> =5V, I <sub>D</sub> =10A
Dynamic					
Ciss	-	767	-	pF	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz
Coss	-	505	-		
Crss	-	65	-		
*td(ON)	-	9.2	-	ns	V <sub>DS</sub> =15V, I <sub>D</sub> =15A, V <sub>GS</sub> =10V, R <sub>GS</sub> =1 Ω
*tr	-	12.6	-		
*td(OFF)	-	24.2	-		
*tf	-	5.8	-		
*Qg	-	14	-	nC	V <sub>DS</sub> =15V, I <sub>D</sub> =15A, V <sub>GS</sub> =10V
*Qgs	-	2.9	-		
*Qgd	-	2.8	-		
Rg	-	0.7	-	Ω	f=1MHz
Body Diode					
*I <sub>S</sub>	-	-	22	A	
*V <sub>SD</sub>	-	0.82	1.1	V	V <sub>GS</sub> =0V, I <sub>S</sub> =10A
*t <sub>rr</sub>	-	18.8	-	ns	I <sub>F</sub> =10A, V <sub>GS</sub> =0V, dI <sub>F</sub> /dt=100A/μs
*Q <sub>rr</sub>	-	6.6	-	nC	

Note : \*1.Pulse Test : Pulse Width ≤300μs, Duty Cycle≤2%  
 \*2.Independent of operating temperature  
 \*3.Pulse width limited by maximum junction temperature.

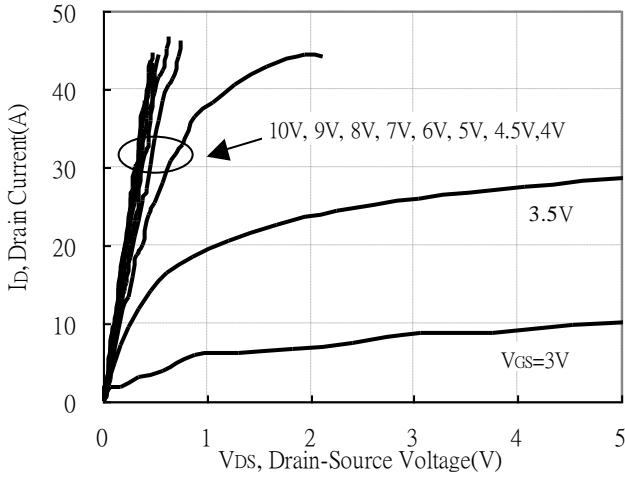
### Recommended Soldering Footprint



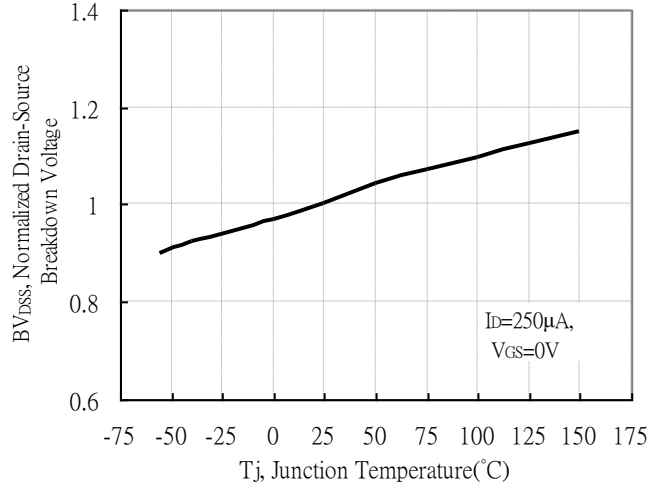
unit : mm

**Typical Characteristics : Q1( N-channel )**

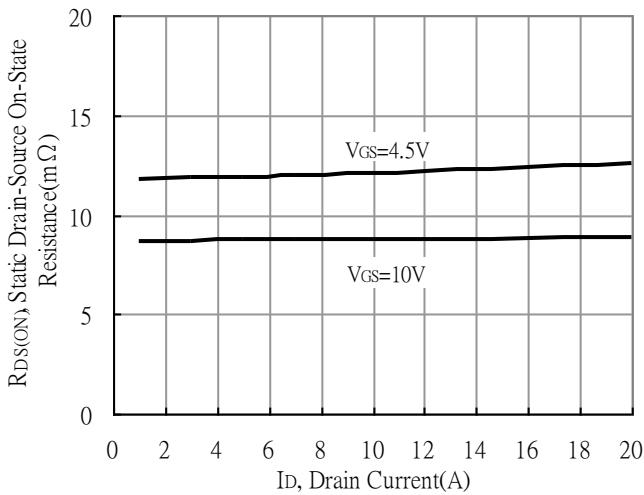
Typical Output Characteristics



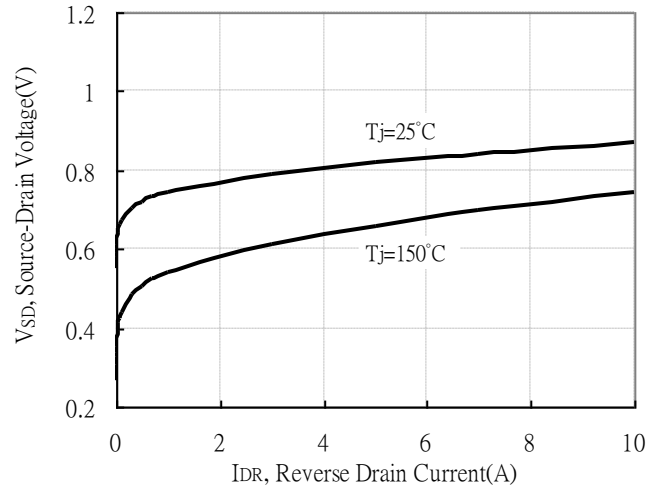
Brekdown Voltage vs Ambient Temperature



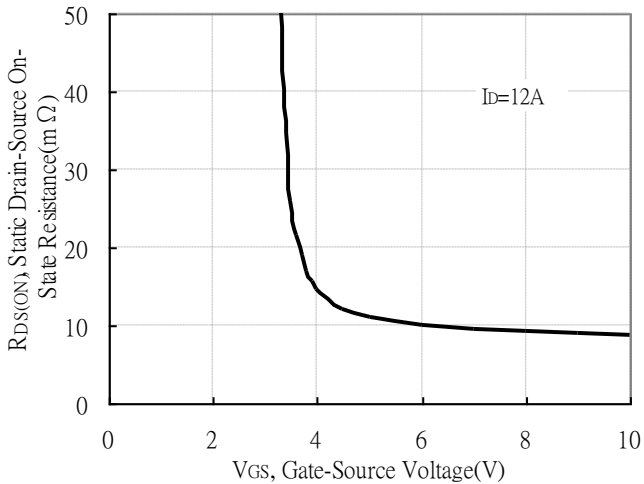
Static Drain-Source On-State resistance vs Drain Current



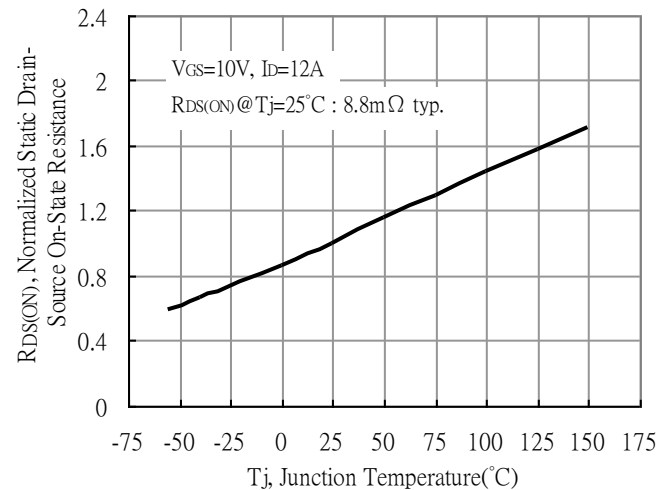
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage

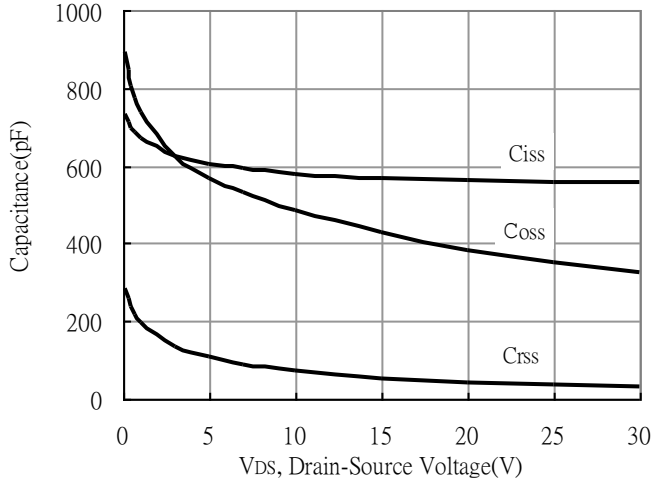


Drain-Source On-State Resistance vs Junction Temperature

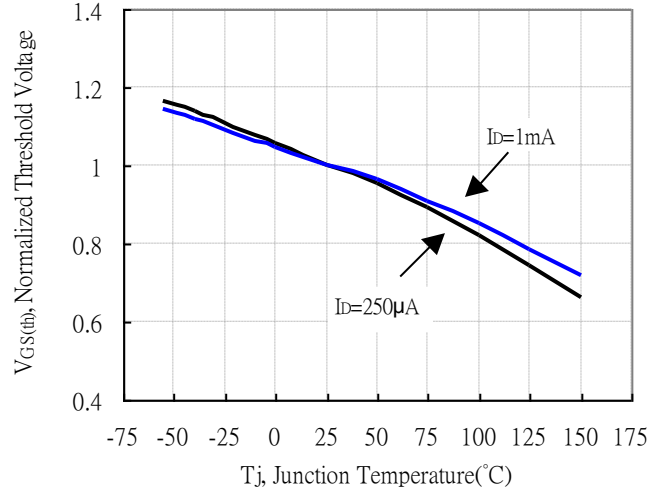


## Typical Characteristics(Cont.) : Q1( N-channel)

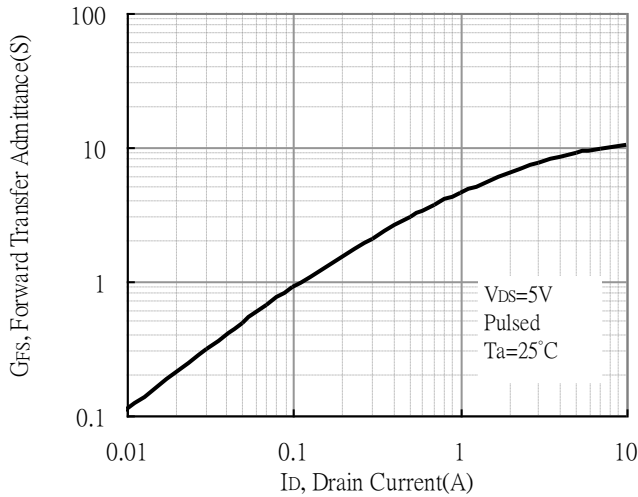
Capacitance vs Drain-to-Source Voltage



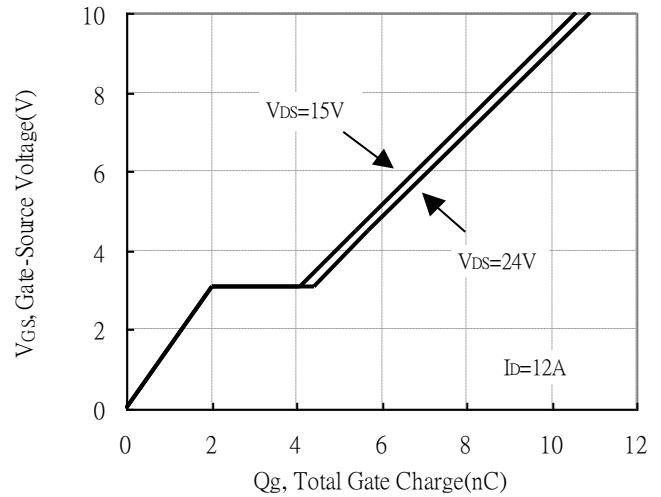
Threshold Voltage vs Junction Temperature



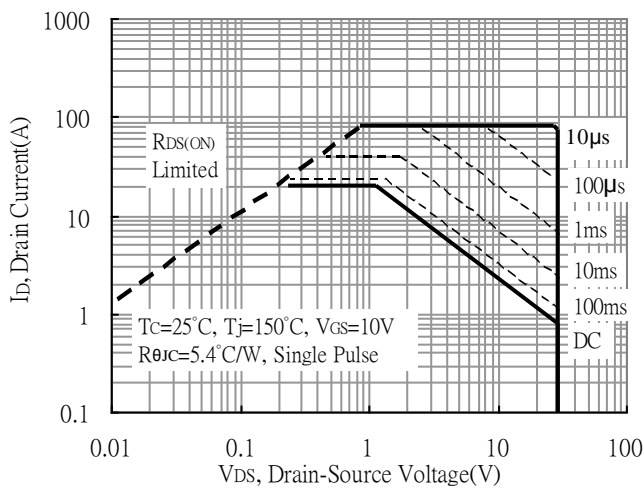
Forward Transfer Admittance vs Drain Current



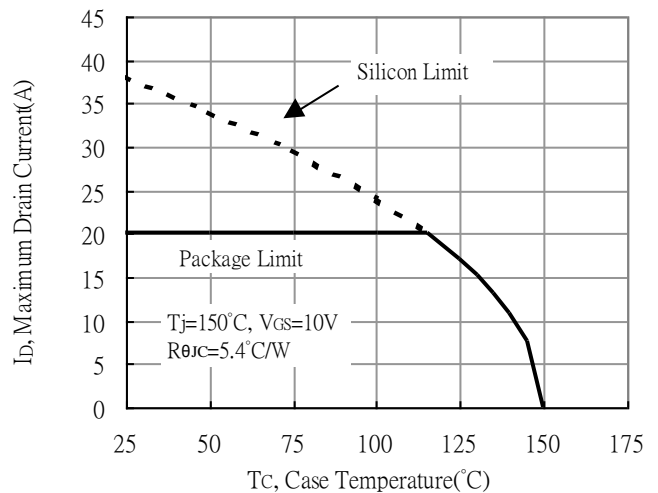
Gate Charge Characteristics



Maximum Safe Operating Area

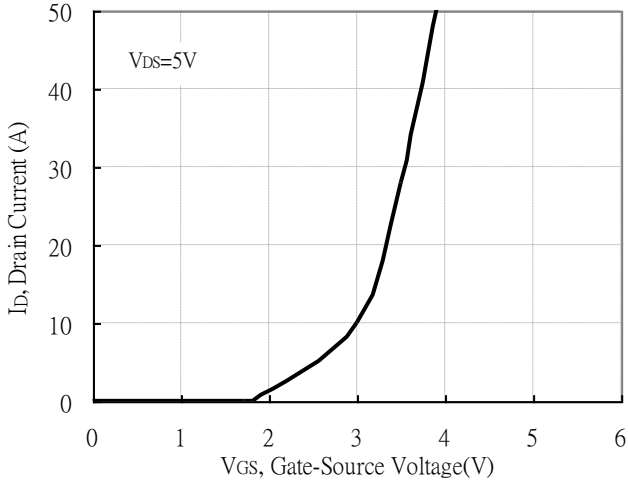


Maximum Drain Current vs Case Temperature

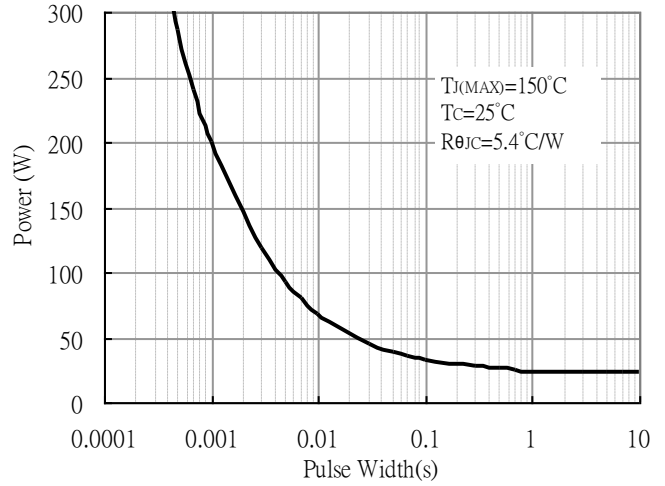


**Typical Characteristics(Cont.) : Q1( N-channel)**

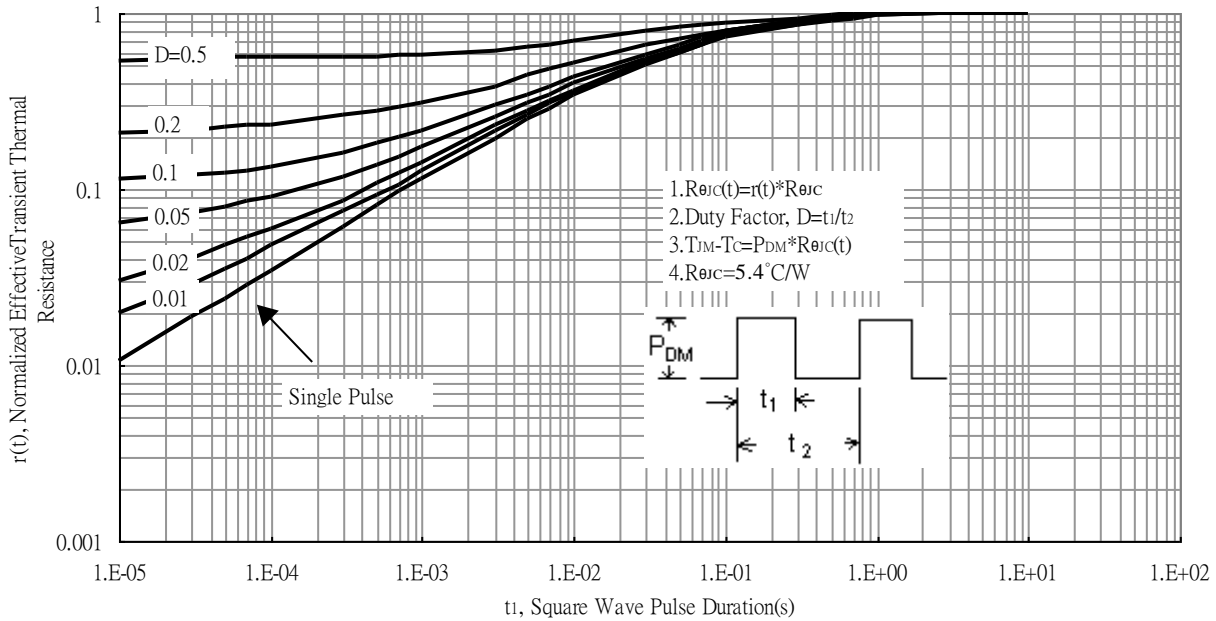
Typical Transfer Characteristics



Single Pulse Power Rating, Junction to Case



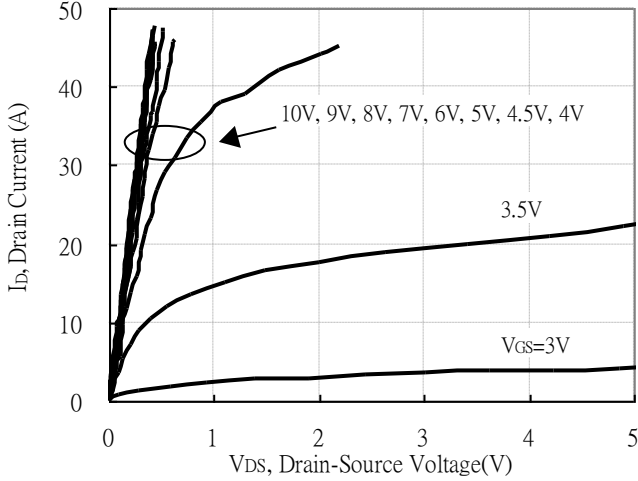
Transient Thermal Response Curves



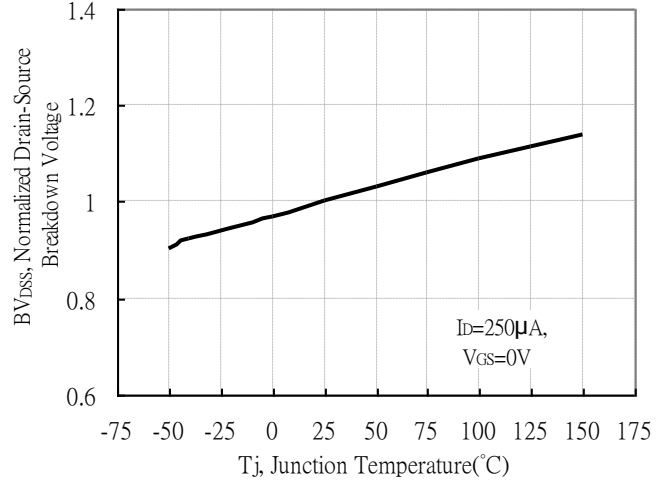


**Typical Characteristics : Q2( N-channel)**

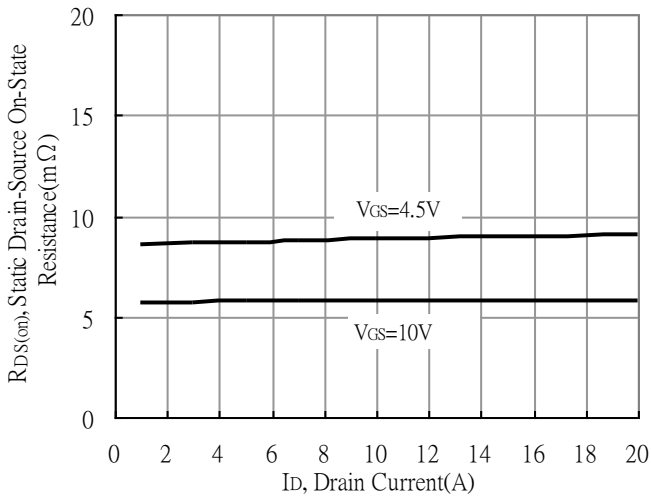
Typical Output Characteristics



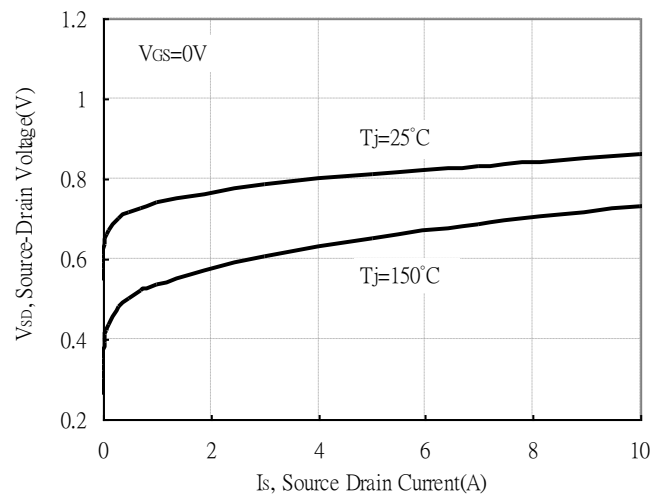
Brekdown Voltage vs Ambient Temperature



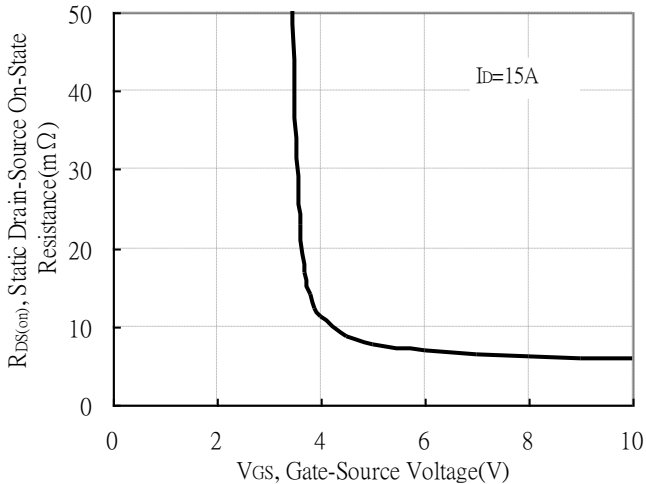
Static Drain-Source On-State resistance vs Drain Current



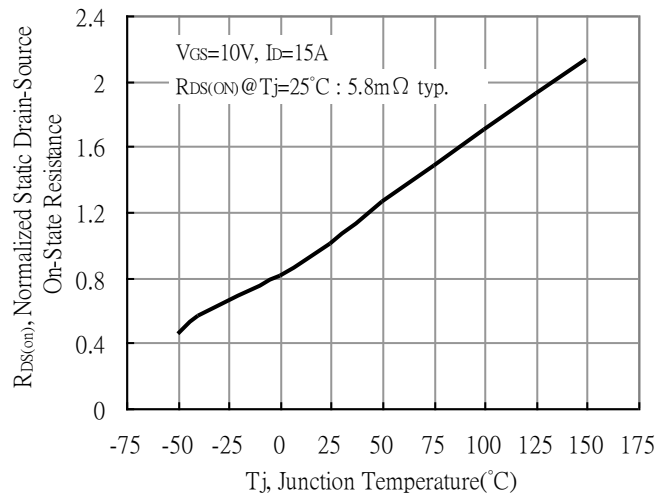
Source Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage



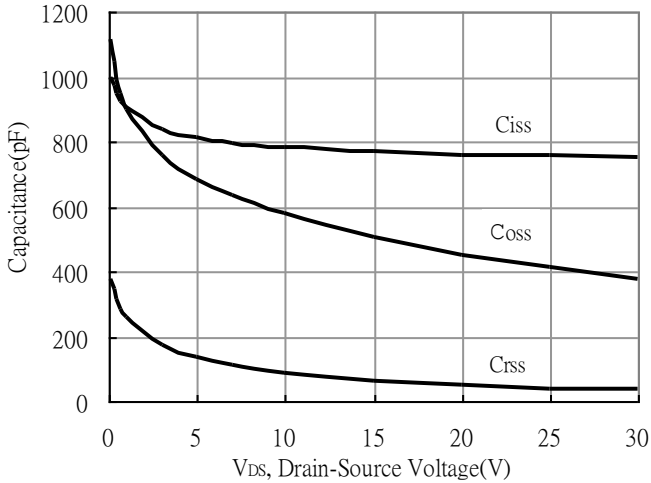
Drain-Source On-State Resistance vs Junction Temperature



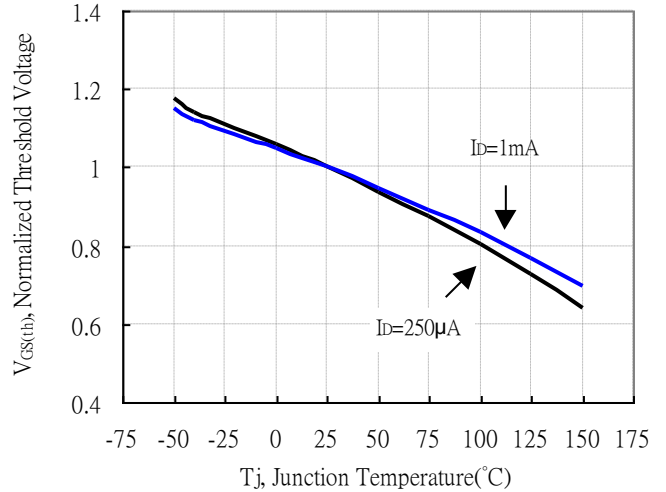


## Typical Characteristics(Cont.) : Q2(N-channel)

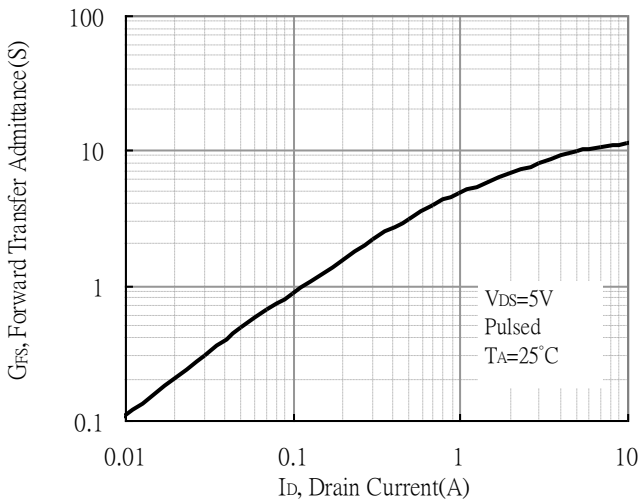
Capacitance vs Drain-to-Source Voltage



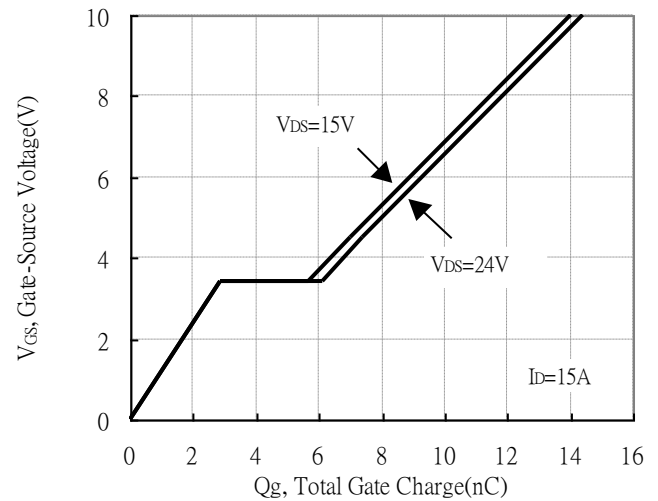
Threshold Voltage vs Junction Temperature



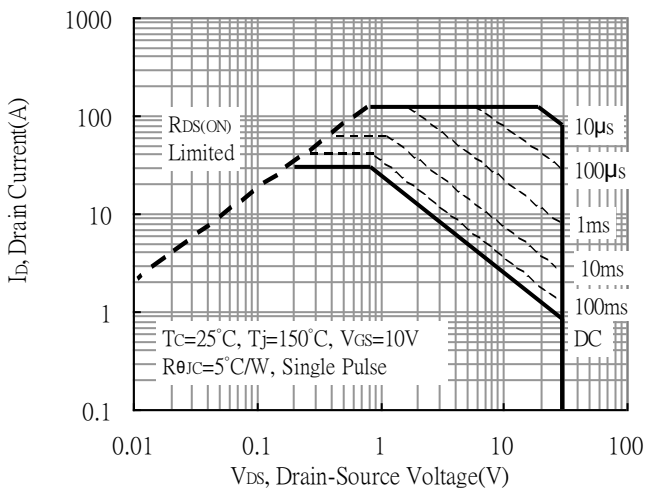
Forward Transfer Admittance vs Drain Current



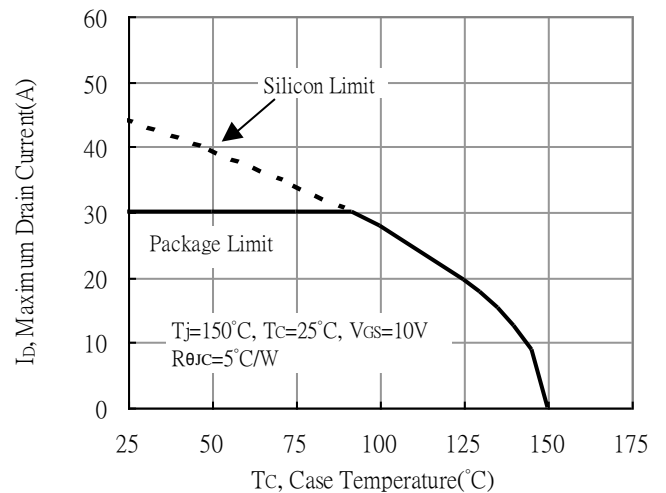
Gate Charge Characteristics



Maximum Safe Operating Area



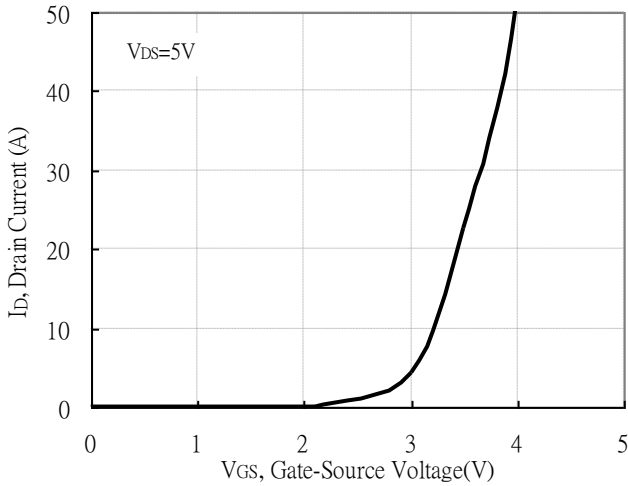
Maximum Drain Current vs Case Temperature



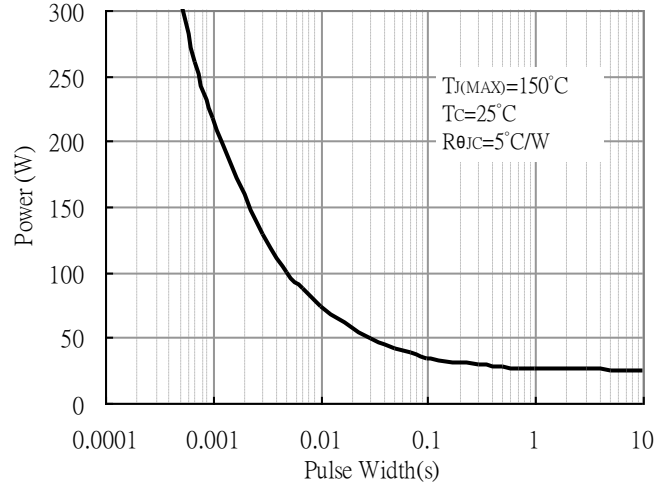


**Typical Characteristics(Cont.) : Q2(P-channel)**

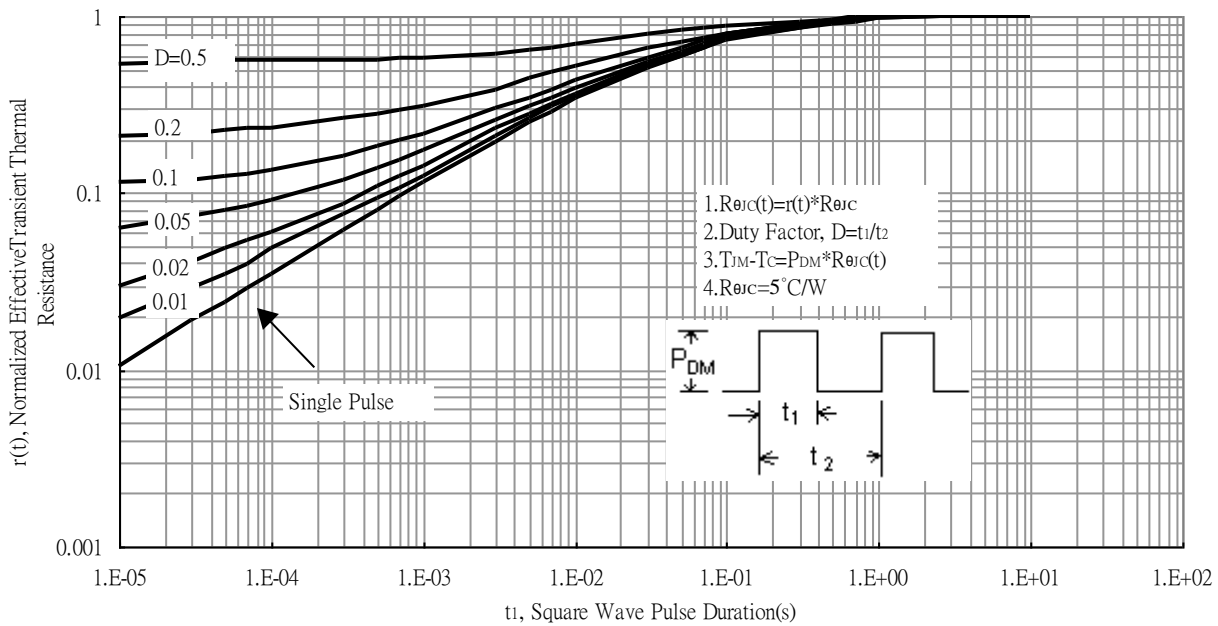
Typical Transfer Characteristics



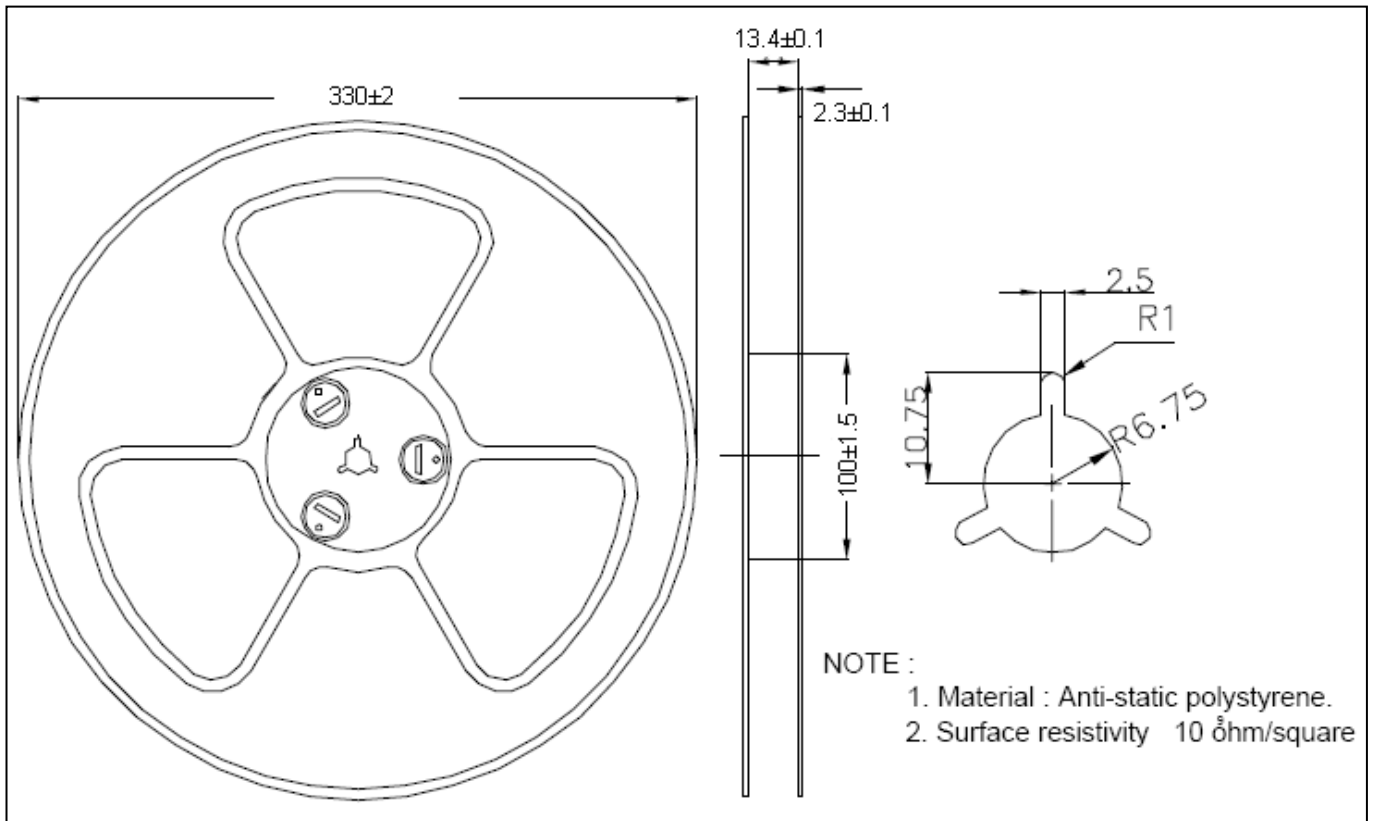
Single Pulse Power Rating, Junction to Case



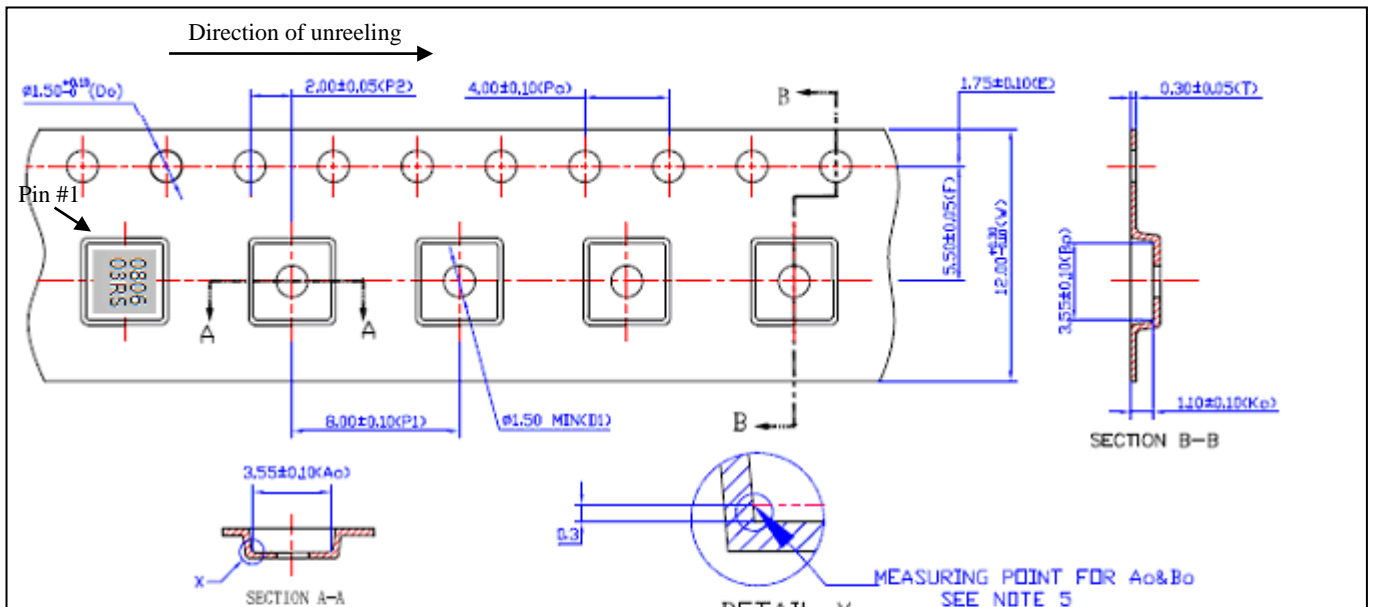
Transient Thermal Response Curves



**Reel Dimension**



**Carrier Tape**

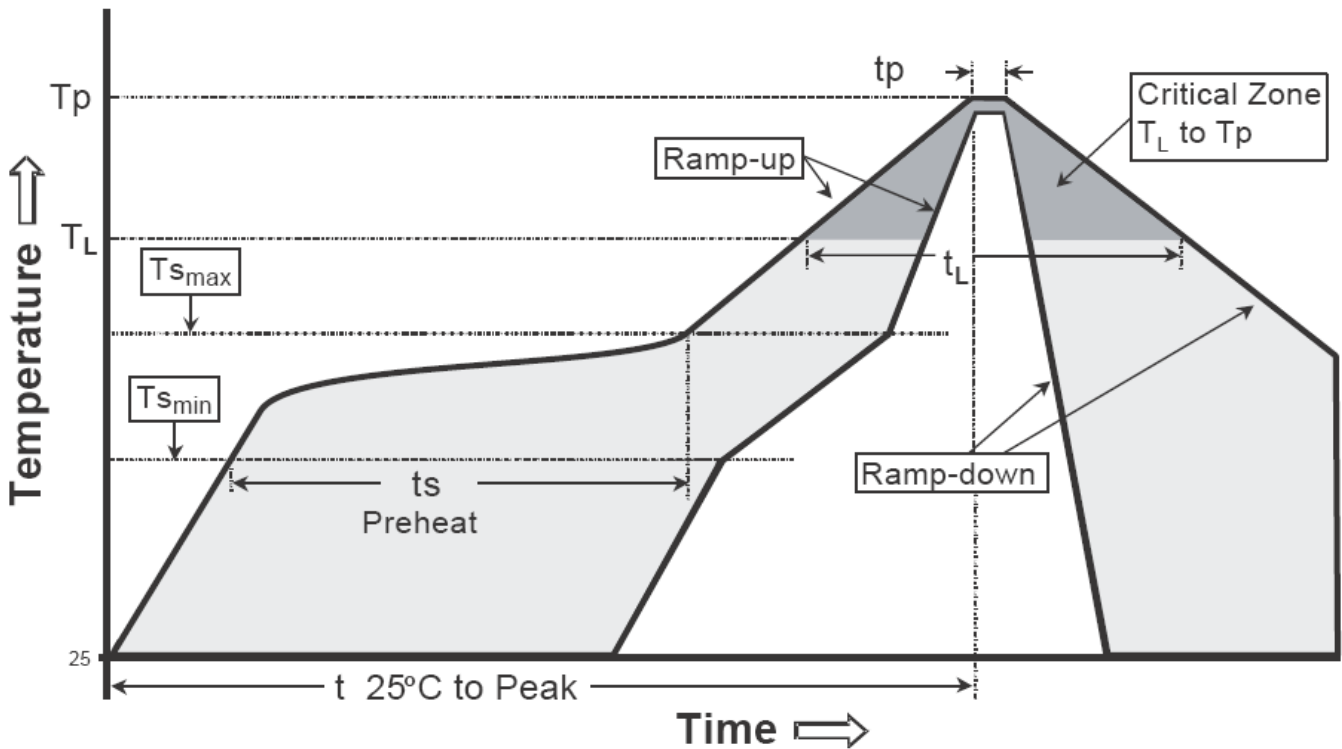


- Note :
- 1.10 sprocket hole pitch cumulative tolerance :  $\pm 0.2\text{mm}$ .
  - 2.Camber : Reference to carrier tape inspection manual.
  - 3.Material : black conductive polystyrene.
  - 4.All dimensions are in millimeters(unless otherwise specified).
  - 5.Ao and Bo measured on a plane 0.3mm above the bottom of the pocket.
  - 6.Ko measured from a plane on the inside bottom of the pocket to the top surface of the carrier.
  - 7.Pocket position relative to sprocket hole measured as true position of the pocket, not pocket hole.
  - 8.Surface resistivity :  $1 \times 10^4 \sim 1 \times 10^{11} \text{ ohms/sq}$

**Recommended wave soldering condition**

Product	Peak Temperature	Soldering Time
Pb-free devices	260 +0/-5 °C	5 +1/-1 seconds

**Recommended temperature profile for IR reflow**



Profile feature	Sn-Pb eutectic Assembly	Pb-free Assembly
Average ramp-up rate (Tsmmax to Tp)	3°C/second max.	3°C/second max.
Preheat		
-Temperature Min(Ts min)	100°C	150°C
-Temperature Max(Ts max)	150°C	200°C
-Time(ts min to ts max)	60-120 seconds	60-180 seconds
Time maintained above:		
-Temperature (Tl)	183°C	217°C
- Time (tl)	60-150 seconds	60-150 seconds
Peak Temperature(Tp)	240 +0/-5 °C	260 +0/-5 °C
Time within 5°C of actual peak temperature(tp)	10-30 seconds	20-40 seconds
Ramp down rate	6°C/second max.	6°C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.

Note : All temperatures refer to topside of the package, measured on the package body surface.

**DFN3x3 Dimension**

**Marking:**

G2 S2 S2 S2

**0806**

**03RS**

□□□□ X

●

Assembly site code:  
 blank→site 1  
 G→site 2

G1 D1 D1 D1

Date Code →

Note : 1.All dimensions are in mm.  
 2.Dimensions are not inclusive burrs and mold flash.

**8-Lead DFN3x3 Plastic Package**  
 CYStek Package Code: V8

Date Code(counting from left to right) :  
 1<sup>st</sup> code: year code, the last digit of Christian year  
 2<sup>nd</sup> code : month code, Jan→A, Feb→B, Mar→C, Apr→D  
 May→E, Jun→F, Jul→G, Aug→H, Sep→J,  
 Oct→K, Nov→L, Dec→M  
 3<sup>rd</sup> and 4<sup>th</sup> codes : production serial number, 01~99

DIM	Millimeters		Inches		DIM	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.70	0.80	0.028	0.032	E	2.90	3.10	0.114	0.122
A1	0.00	0.05	0.000	0.002	E1	2.20	2.40	0.087	0.094
b	0.35	0.45	0.014	0.018	E2	2.20	2.45	0.087	0.096
c	0.20	REF	0.008	REF	e	0.55	0.75	0.008	0.030
D	2.90	3.10	0.114	0.122	K	0.15	0.35	0.006	0.014
D1	0.40	0.60	0.016	0.024	K1	0.25	0.45	0.010	0.018
D2	0.85	1.05	0.033	0.041	L	0.27	0.40	0.011	0.016

**Notes:** 1.Controlling dimension: millimeters.  
 2.Maximum lead thickness includes lead finish thickness, and minimum lead thickness is the minimum thickness of base material.  
 3.If there is any question with packing specification or packing method, please contact your local CYStek sales office.

**Material:**

- Lead: pure tin plated.
- Mold Compound: Epoxy resin family, flammability solid burning class: UL94V-0.

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